Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination					
10/720,354	HAMA ET AL.					
Examiner	Art Unit					
Tran N. Nguyen	2834					

	SEAF	RCHED			SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
Class	Subclass	Date	Examiner			-		DATE	EXMR
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INTERFERENCE SEARCHED									
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